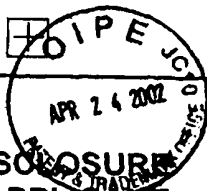


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Substitute for form 1449A/B/PTO

# **INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet 1 of 1

## **Complete If Known**

Application Number	10/030,317
Filing Date	October 19, 2001
First Named Inventor	Alan J. SMITH
Group Art Unit	Unassigned
Examiner Name	Unassigned
Attorney Docket Number	213649

## **U.S. PATENT DOCUMENTS**

Examiner Initials	Doc. No.	U.S. Patent Document		Name of Patentee or Applicant	Date of Publication	Filing Date If Appropriate
		Application or Patent Number	Kind Code			
W	AA	4,322,621		Aagard	3/30/1982	
W	AB	5,220,402		Harvey	6/15/1993	
W	AC	5,485,276		Bien et al.	1/16/1996	
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W	AE	5,742,054		Atkinson	4/21/1998	
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W	AI	5,841,533		Atkinson	11/24/1998	
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## **FOREIGN PATENT DOCUMENTS**

Examiner Initials	Doc. No.	Foreign Patent Document			Name of Patentee or Applicant	Date of Publication	Translation	
		Office	Application or Patent Number	Kind Code			Yes	No**
W	AK	JP	55039049		Matsushita Electric Ind. Co. Ltd.	03/18/1980	X	
W	AL	DE	90 17 745.2		Drägerwerk AG	12/7/1990	X	
W	AM	DE	42 14 840	A1	Drägerwerk AG	5/5/1992	X	
W	AN	WO	93/13401		Gaztech International Corporation	7/8/1993		
W	AO	JP	05296934		Sanyo Electric Co. Ltd.	11/12/1993	X	

## **OTHER - NON PATENT LITERATURE DOCUMENTS**

Examiner Initials	Doc. No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number (s), publisher, city and/or country where published.	Translation	
			Yes	No**
W	AP	Anderson et al., "Mirror reflectometer based on optical cavity decay time," <i>Applied Optics</i> , 23:1238-1244 (1984)		
W	AQ	Herbelin et al., "Sensitive measurement of photon lifetime and true reflectances in an optical cavity by a phase-shift method," <i>Applied Optics</i> , 19:144-147 (1980)		
W	AR	Hodges et al., "Laser bandwidth effects in quantitative cavity ring-down spectroscopy," <i>Applied Optics</i> , 35:4112-4117 (1996)		
W	AS	Jongma et al., "Trace gas detection with cavity ring down spectroscopy," <i>Rev. Sci. Instrum.</i> , 68:2821-2828 (1995)		
W	AT	O'Keefe and Deacon, "Cavity ring-down optical spectrometer for absorption measurements using pulsed laser sources," <i>Rev. Sci. Instrum.</i> , 59:2544-2551 (1988)		
W	AU	Scherer et al., "Cavity Ringdown Laser Absorption Spectroscopy: History, Development, and Application to Pulsed Molecular Beams," <i>Chem. Rev.</i> , 97:25-51 (1997)		
W	AV	White, "Long Optical Paths of Large Aperture," <i>J.O.S.A.</i> , 32:285-288 (1942)		
W	AW	Zalicki and Zare, "Cavity ring-down spectroscopy for quantitative absorption measurements," <i>J. Chem. Phys.</i> , 102:2708-2717 (1995)		

Examiner Signature	<i>Richard Reiberger</i>	Date Considered	14 Nov 2003
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\* A concise statement of relevance is being submitted in lieu of a translation. 37 CFR 1.98(a)(3).

+ An English-language equivalent/patent, or an English-language abstract, or an English-language version of the search report or action by a foreign patent office in a counterpart foreign application indicating the degree of relevance found by the foreign office is being submitted in lieu of a concise explanation of relevance under 37 CFR 1.98(a)(3).